



# ACTT16X-800CTN

Enhanced, high temperature ACTT power switch

30 July 2015

Product data sheet

## 1. General description

Planar passivated AC Thyristor Triac power switch in a SOT186A (TO-220F) "full pack" plastic package with self-protective capabilities against low and high energy transients. This "series CTN" triac will commute the full RMS current at the maximum rated junction temperature ( $T_{j(max)} = 150\text{ }^{\circ}\text{C}$ ) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

## 2. Features and benefits

- Clamping structure ensuring safe high over-voltage withstand capability
- High junction operating temperature capability ( $T_{j(max)} = 150\text{ }^{\circ}\text{C}$ )
- High minimum  $I_{GT}$  for guaranteed immunity to gate noise
- Full cycle AC conduction
- Over-voltage withstand capability to IEC 61000-4-5
- Pin compatible with standard triacs
- Planar passivated for voltage ruggedness and reliability
- Protective self turn-on capability for high energy transients
- Safe clamping capability for low energy over-voltage transients
- Less sensitive gate for high noise immunity
- Triggering in three quadrants only
- Very high immunity to false turn-on by  $dV/dt$  and IEC 61000-4-4 fast transient
- Package meets UL94V0 flammability requirement
- Package is RoHS compliant
- Package meets UL1557 isolation test requirement rated at 2500V RMS

## 3. Applications

- AC fan, pump and compressor controls
- Highly inductive, resistive and safety loads
- Large and small appliances (White Goods)
- Reversing induction motor controls
- Applications subject to high temperature ( $T_{j(max)} = 150\text{ }^{\circ}\text{C}$ )

## 4. Quick reference data

Table 1. Quick reference data

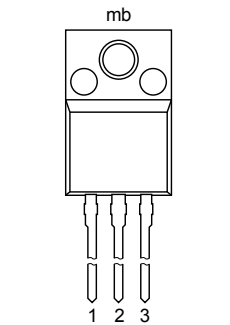
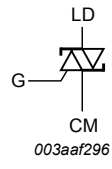
| Symbol    | Parameter                         | Conditions | Min | Typ | Max | Unit |
|-----------|-----------------------------------|------------|-----|-----|-----|------|
| $V_{DRM}$ | repetitive peak off-state voltage |            | -   | -   | 800 | V    |



| Symbol                         | Parameter                             | Conditions   | Min  | Typ | Max | Unit             |
|--------------------------------|---------------------------------------|--|------|-----|-----|------------------|
| $I_{T(RMS)}$                   | RMS on-state current                  | full sine wave; $T_h \leq 70\text{ }^\circ\text{C}$ ; <a href="#">Fig. 1</a> ; <a href="#">Fig. 2</a> ; <a href="#">Fig. 3</a>   | -    | -   | 16  | A                |
| $I_{TSM}$                      | non-repetitive peak on-state current  | full sine wave; $T_{j(\text{init})} = 25\text{ }^\circ\text{C}$ ; $t_p = 20\text{ ms}$ ; <a href="#">Fig. 4</a> ; <a href="#">Fig. 5</a>                                   | -    | -   | 140 | A                |
|                                |                                       | full sine wave; $T_{j(\text{init})} = 25\text{ }^\circ\text{C}$ ; $t_p = 16.7\text{ ms}$   | -    | -   | 150 | A                |
| $T_j$                          | junction temperature                  |  | -    | -   | 150 | $^\circ\text{C}$ |
| $V_{PP}$                       | peak pulse voltage                    | $T_j = 25\text{ }^\circ\text{C}$ ; non-repetitive, off-state; <a href="#">Fig. 6</a>   | -    | -   | 2   | kV               |
| <b>Static characteristics</b>  |                                       |  |      |     |     |                  |
| $I_{GT}$                       | gate trigger current                  | $V_D = 12\text{ V}$ ; $I_T = 100\text{ mA}$ ; LD+ G+; $T_j = 25\text{ }^\circ\text{C}$ ; <a href="#">Fig. 8</a>  | 5    | -   | 35  | mA               |
|                                |                                       | $V_D = 12\text{ V}$ ; $I_T = 100\text{ mA}$ ; LD+ G-; $T_j = 25\text{ }^\circ\text{C}$ ; <a href="#">Fig. 8</a>  | 5    | -   | 35  | mA               |
|                                |                                       | $V_D = 12\text{ V}$ ; $I_T = 100\text{ mA}$ ; LD- G-; $T_j = 25\text{ }^\circ\text{C}$ ; <a href="#">Fig. 8</a>  | 5    | -   | 35  | mA               |
| $I_H$                          | holding current                       | $V_D = 12\text{ V}$ ; $T_j = 25\text{ }^\circ\text{C}$ ; <a href="#">Fig. 10</a>   | -    | -   | 30  | mA               |
| $V_T$                          | on-state voltage                      | $I_T = 20\text{ A}$ ; $T_j = 25\text{ }^\circ\text{C}$ ; <a href="#">Fig. 11</a>   | -    | -   | 1.5 | V                |
| $V_{CL}$                       | clamping voltage                      | $I_{CL} = 0.1\text{ mA}$ ; $t_p = 1\text{ ms}$ ; $T_j = 25\text{ }^\circ\text{C}$  | 850  | -   | -   | V                |
| <b>Dynamic characteristics</b> |                                       |  |      |     |     |                  |
| $dV_D/dt$                      | rate of rise of off-state voltage     | $V_{DM} = 536\text{ V}$ ; $T_j = 125\text{ }^\circ\text{C}$ ; ( $V_{DM} = 67\%$ of $V_{DRM}$ ); exponential waveform; gate open circuit                                    | 1500 | -   | -   | V/ $\mu\text{s}$ |
|                                |                                       | $V_{DM} = 536\text{ V}$ ; $T_j = 150\text{ }^\circ\text{C}$ ; exponential waveform; gate open circuit  | 1000 | -   | -   | V/ $\mu\text{s}$ |
| $dI_{com}/dt$                  | rate of change of commutating current | $V_D = 400\text{ V}$ ; $T_j = 150\text{ }^\circ\text{C}$ ; $I_{T(RMS)} = 16\text{ A}$ ; $dV_{com}/dt = 20\text{ V}/\mu\text{s}$ ; gate open circuit; snubberless condition | 12   | -   | -   | A/ms             |
|                                |                                       | $V_D = 400\text{ V}$ ; $T_j = 150\text{ }^\circ\text{C}$ ; $I_{T(RMS)} = 16\text{ A}$ ; $dV_{com}/dt = 10\text{ V}/\mu\text{s}$ ; gate open circuit                        | 15   | -   | -   | A/ms             |
|                                |                                       | $V_D = 400\text{ V}$ ; $T_j = 150\text{ }^\circ\text{C}$ ; $I_{T(RMS)} = 16\text{ A}$ ; $dV_{com}/dt = 1\text{ V}/\mu\text{s}$ ; gate open circuit                         | 20   | -   | -   | A/ms             |

## 5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description             | Simplified outline   | Graphic symbol   |
|-----|--------|-------------------------|--|--|
| 1   | CM     | common                  |  <p>TO-220F (SOT186A)</p> |  <p>003aaf296</p> |
| 2   | LD     | load                    |  |  |
| 3   | G      | gate                    |  |  |
| mb  | n.c.   | mounting base; isolated |  |  |

## 6. Ordering information

Table 3. Ordering information

| Type number    | Package |   |         |
|----------------|---------|---|---------|
|                | Name    | Description   | Version |
| ACTT16X-800CTN | TO-220F | plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 "full pack" | SOT186A |

## 7. Marking

Table 4. Marking codes

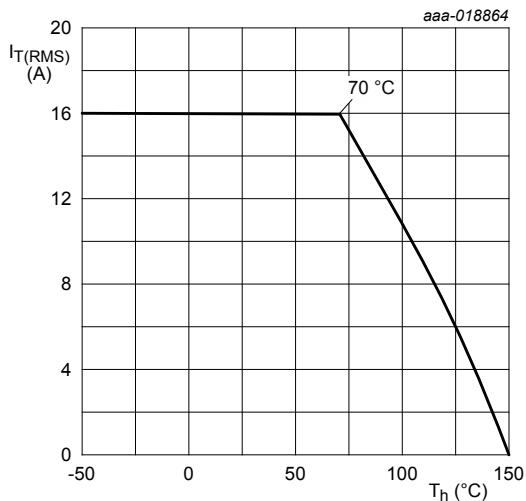
| Type number    | Marking code   |
|----------------|----------------|
| ACTT16X-800CTN | ACTT16X-800CTN |

## 8. Limiting values

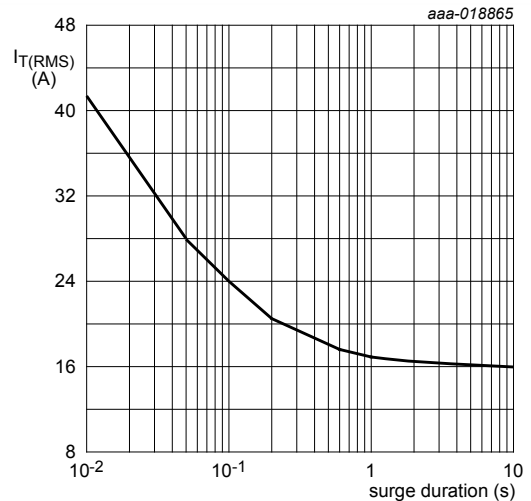
**Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol       | Parameter                            | Conditions  | Min | Max | Unit             |
|--------------|--------------------------------------|---|-----|-----|------------------|
| $V_{DRM}$    | repetitive peak off-state voltage    |   | -   | 800 | V                |
| $I_{T(RMS)}$ | RMS on-state current                 | full sine wave; $T_h \leq 70\text{ °C}$ ; <a href="#">Fig. 1</a> ; <a href="#">Fig. 2</a> ; <a href="#">Fig. 3</a>    | -   | 16  | A                |
| $I_{TSM}$    | non-repetitive peak on-state current | full sine wave; $T_{j(init)} = 25\text{ °C}$ ; $t_p = 20\text{ ms}$ ; <a href="#">Fig. 4</a> ; <a href="#">Fig. 5</a> | -   | 140 | A                |
|              |                                      | full sine wave; $T_{j(init)} = 25\text{ °C}$ ; $t_p = 16.7\text{ ms}$   | -   | 150 | A                |
| $I^2t$       | $I^2t$ for fusing                    | $t_p = 10\text{ ms}$ ; sine-wave pulse  | -   | 98  | A <sup>2</sup> s |
| $di_T/dt$    | rate of rise of on-state current     | $I_G = 70\text{ mA}$  | -   | 100 | A/ $\mu$ s       |
| $I_{GM}$     | peak gate current                    |   | -   | 2   | A                |
| $P_{GM}$     | peak gate power                      |   | -   | 5   | W                |
| $P_{G(AV)}$  | average gate power                   | over any 20 ms period   | -   | 0.5 | W                |
| $T_{stg}$    | storage temperature                  |   | -40 | 150 | °C               |
| $T_j$        | junction temperature                 |   | -   | 150 | °C               |
| $V_{PP}$     | peak pulse voltage                   | $T_j = 25\text{ °C}$ ; non-repetitive, off-state; <a href="#">Fig. 6</a>  | -   | 2   | kV               |



**Fig. 1. RMS on-state current as a function of heatsink temperature; maximum values**



$f = 50\text{ Hz}$ ;  $T_h = 70\text{ °C}$

**Fig. 2. RMS on-state current as a function of surge duration; maximum values**

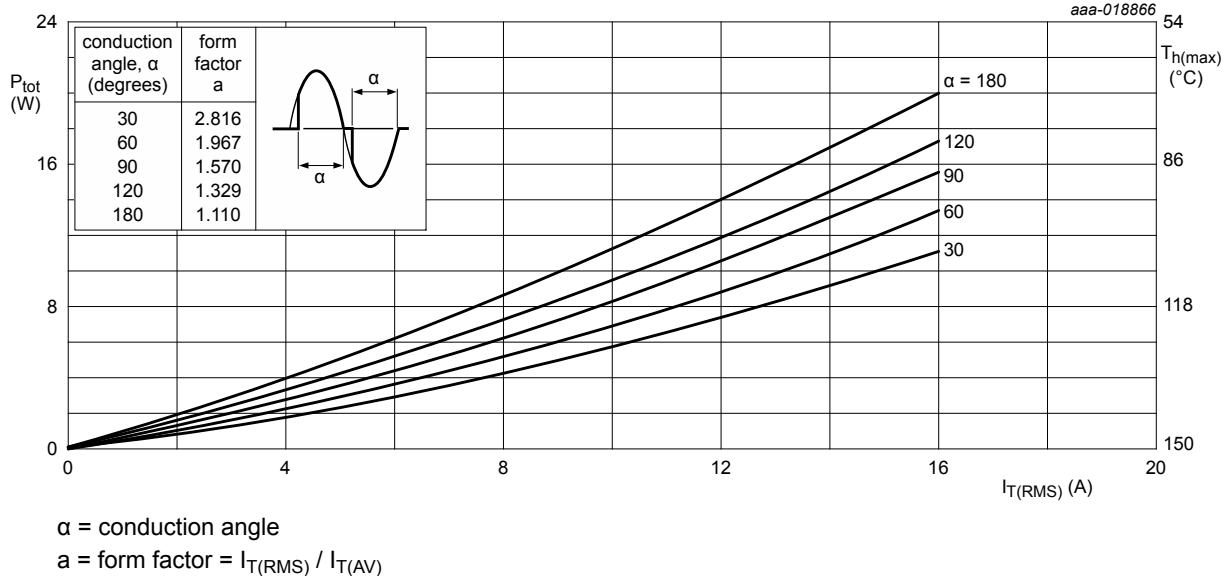


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

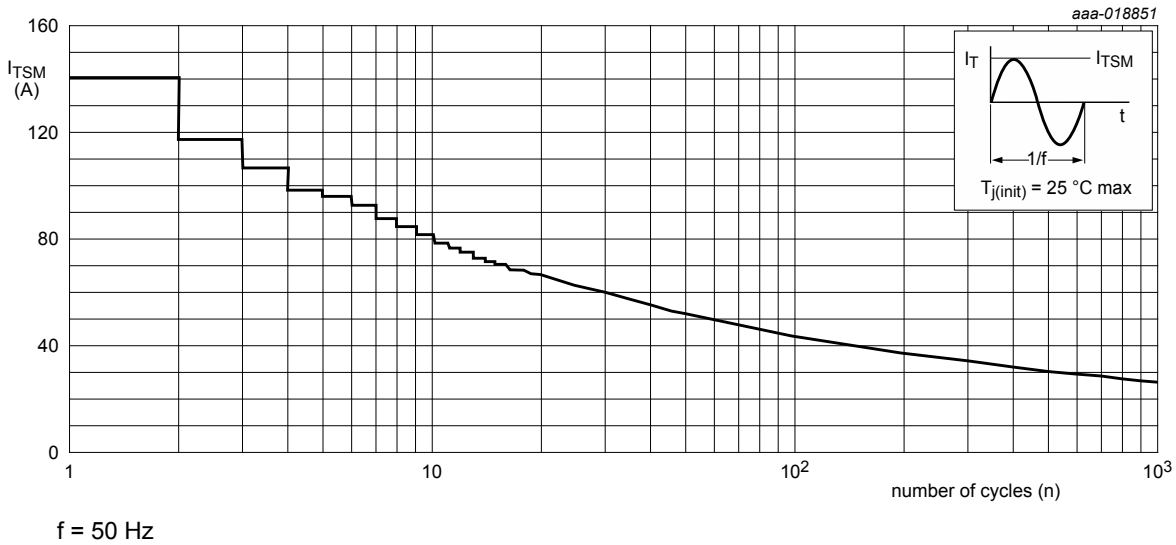


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

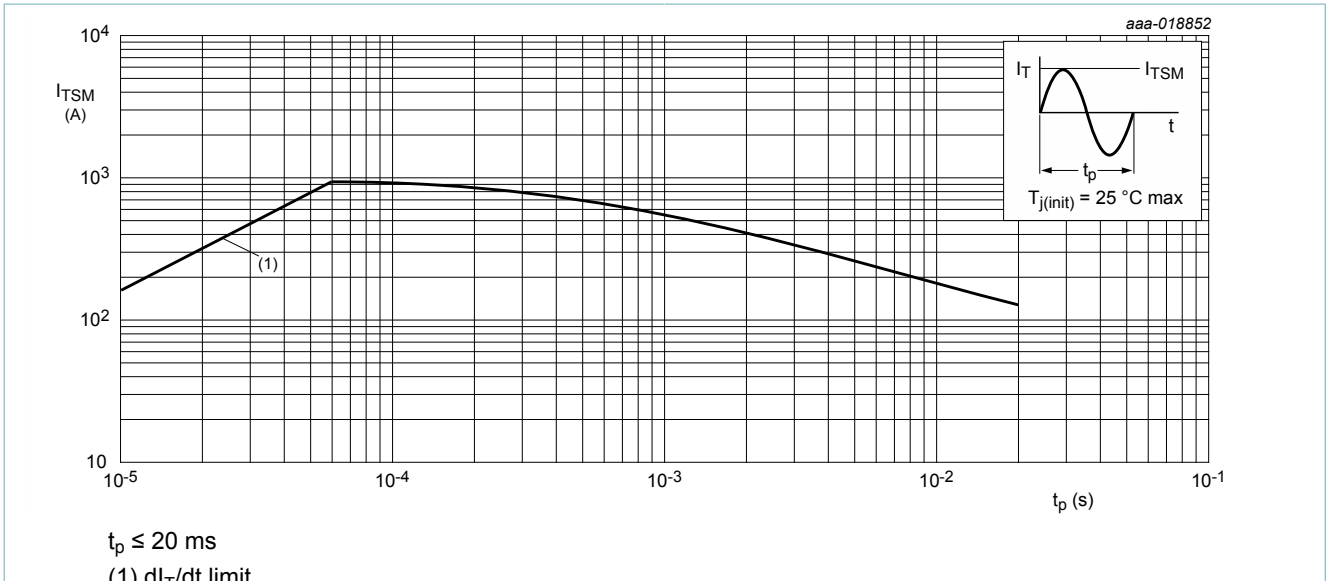


Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

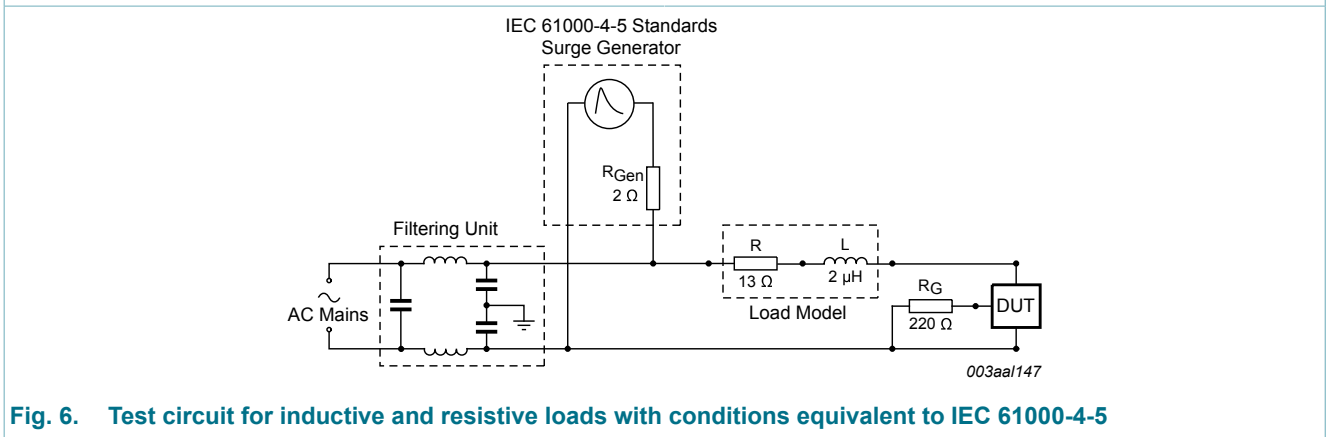


Fig. 6. Test circuit for inductive and resistive loads with conditions equivalent to IEC 61000-4-5

## 9. Thermal characteristics

Table 6. Thermal characteristics

| Symbol        | Parameter  | Conditions   | Min | Typ | Max | Unit |
|---------------|--|--|-----|-----|-----|------|
| $R_{th(j-h)}$ | thermal resistance from junction to heatsink         | full or half cycle; with heatsink compound; <a href="#">Fig. 7</a> | -   | -   | 4   | K/W  |
|               |  | full or half cycle; without heatsink compound                      | -   | -   | 5.5 | K/W  |
| $R_{th(j-a)}$ | thermal resistance from junction to ambient free air | in free air  | -   | 55  | -   | K/W  |

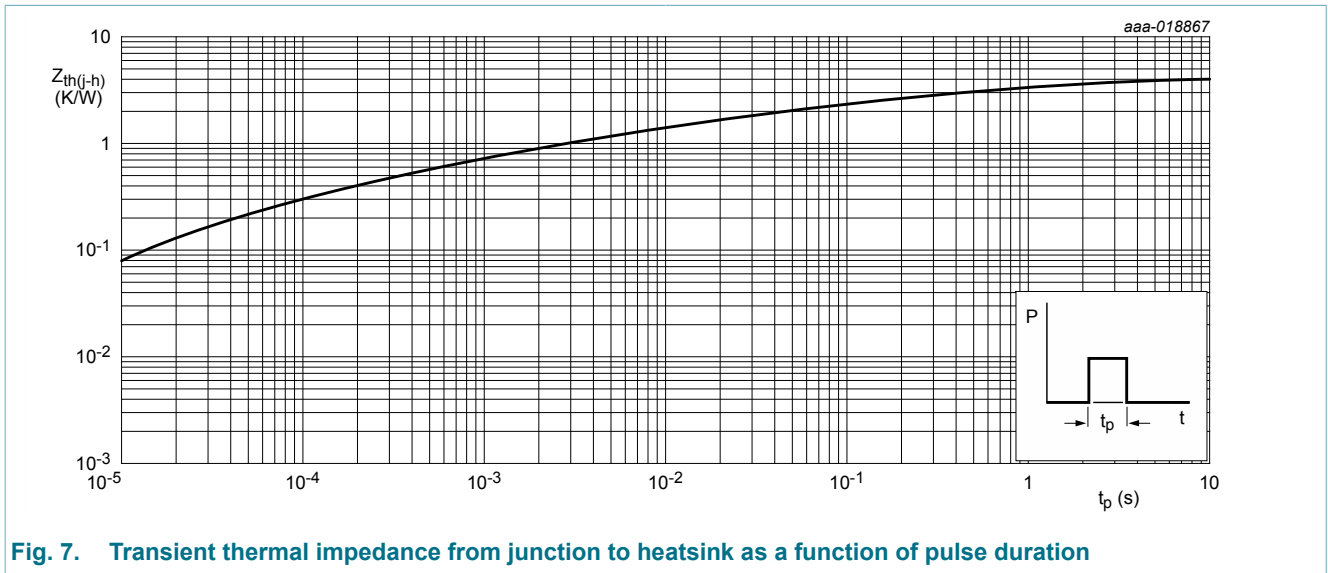


Fig. 7. Transient thermal impedance from junction to heatsink as a function of pulse duration

## 10. Isolation characteristics

Table 7. Isolation characteristics

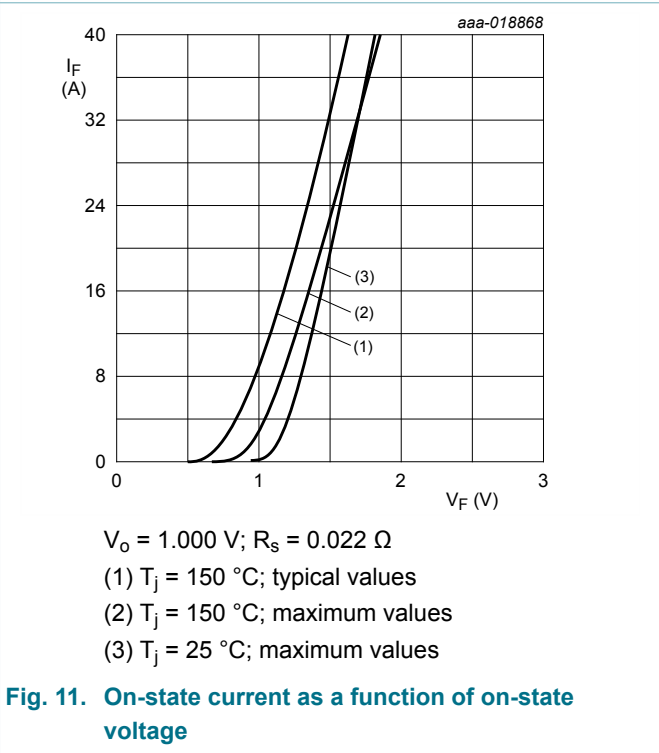
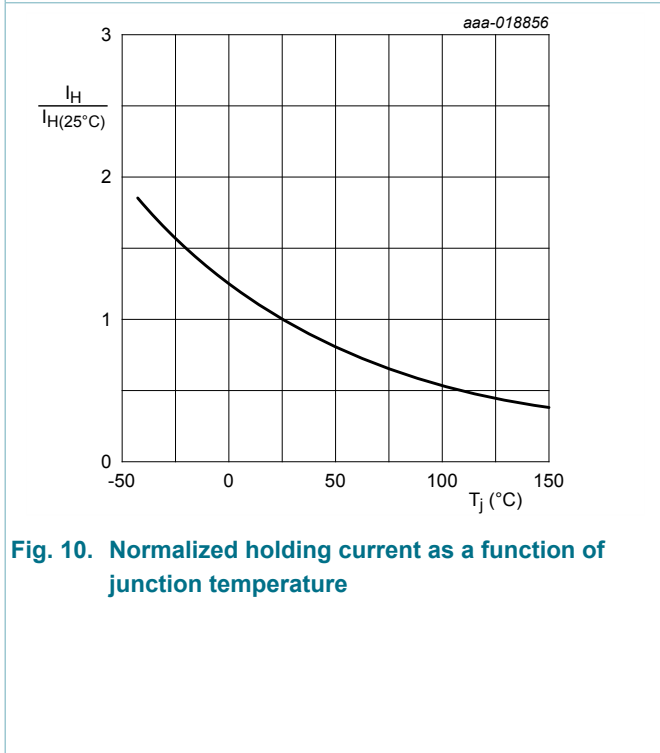
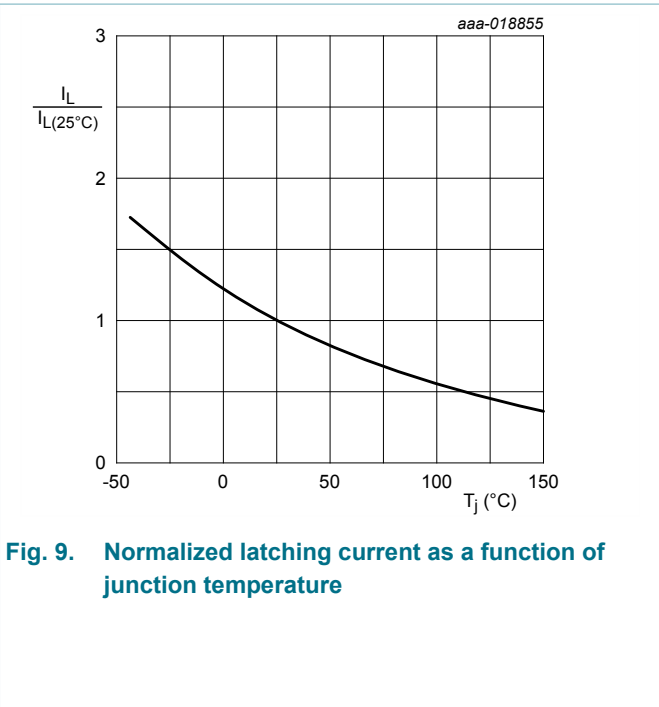
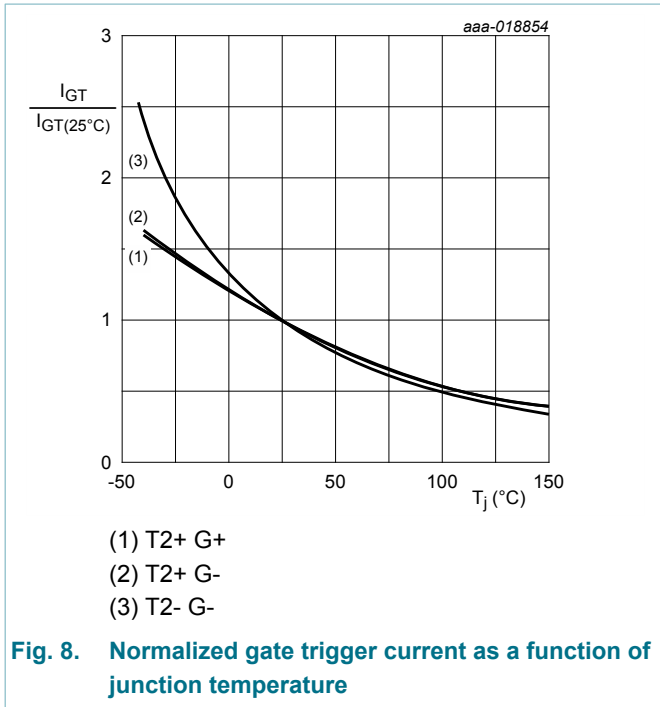
| Symbol          | Parameter             | Conditions  | Min | Typ | Max  | Unit |
|-----------------|-----------------------|---|-----|-----|------|------|
| $V_{isol(RMS)}$ | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; $50\text{ Hz} \leq f \leq 60\text{ Hz}$ ; $T_h = 25\text{ °C}$ | -   | -   | 2500 | V    |
| $C_{isol}$      | isolation capacitance | from main terminal 2 to external heatsink; $f = 1\text{ MHz}$ ; $T_h = 25\text{ °C}$  | -   | 10  | -    | pF   |

## 11. Characteristics

Table 8. Characteristics

| Symbol                         | Parameter                             | Conditions   | Min  | Typ  | Max | Unit |
|--------------------------------|---------------------------------------|--|------|------|-----|------|
| <b>Static characteristics</b>  |                                       |  |      |      |     |      |
| I <sub>GT</sub>                | gate trigger current                  | V <sub>D</sub> = 12 V; I <sub>T</sub> = 100 mA; LD+ G+;<br>T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>  | 5    | -    | 35  | mA   |
|                                |                                       | V <sub>D</sub> = 12 V; I <sub>T</sub> = 100 mA; LD+ G-;<br>T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>  | 5    | -    | 35  | mA   |
|                                |                                       | V <sub>D</sub> = 12 V; I <sub>T</sub> = 100 mA; LD- G-;<br>T <sub>j</sub> = 25 °C; <a href="#">Fig. 8</a>  | 5    | -    | 35  | mA   |
| I <sub>L</sub>                 | latching current                      | V <sub>D</sub> = 12 V; I <sub>G</sub> = 100 mA; LD+ G+;<br>T <sub>j</sub> = 25 °C; <a href="#">Fig. 9</a>  | -    | -    | 40  | mA   |
|                                |                                       | V <sub>D</sub> = 12 V; I <sub>G</sub> = 100 mA; LD+ G-;<br>T <sub>j</sub> = 25 °C; <a href="#">Fig. 9</a>  | -    | -    | 50  | mA   |
|                                |                                       | V <sub>D</sub> = 12 V; I <sub>G</sub> = 100 mA; LD- G-;<br>T <sub>j</sub> = 25 °C; <a href="#">Fig. 9</a>  | -    | -    | 40  | mA   |
| I <sub>H</sub>                 | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <a href="#">Fig. 10</a>   | -    | -    | 30  | mA   |
| V <sub>T</sub>                 | on-state voltage                      | I <sub>T</sub> = 20 A; T <sub>j</sub> = 25 °C; <a href="#">Fig. 11</a>   | -    | -    | 1.5 | V    |
| V <sub>GT</sub>                | gate trigger voltage                  | V <sub>D</sub> = 12 V; I <sub>T</sub> = 100 mA; T <sub>j</sub> = 25 °C;<br><a href="#">Fig. 12</a>   | -    | 0.8  | 1   | V    |
|                                |                                       | V <sub>D</sub> = 400 V; I <sub>T</sub> = 100 mA; T <sub>j</sub> = 150 °C;<br><a href="#">Fig. 12</a>   | 0.2  | 0.45 | -   | V    |
| I <sub>D</sub>                 | off-state current                     | V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C   | -    | -    | 10  | µA   |
|                                |                                       | V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C  | -    | -    | 2   | mA   |
| V <sub>CL</sub>                | clamping voltage                      | I <sub>CL</sub> = 0.1 mA; t <sub>p</sub> = 1 ms; T <sub>j</sub> = 25 °C  | 850  | -    | -   | V    |
| <b>Dynamic characteristics</b> |                                       |  |      |      |     |      |
| dV <sub>D</sub> /dt            | rate of rise of off-state voltage     | V <sub>DM</sub> = 536 V; T <sub>j</sub> = 125 °C; (V <sub>DM</sub> = 67% of V <sub>DRM</sub> ); exponential waveform; gate open circuit                | 1500 | -    | -   | V/µs |
|                                |                                       | V <sub>DM</sub> = 536 V; T <sub>j</sub> = 150 °C; exponential waveform; gate open circuit  | 1000 | -    | -   | V/µs |
| dI <sub>com</sub> /dt          | rate of change of commutating current | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; I <sub>T(RMS)</sub> = 16 A; dV <sub>com</sub> /dt = 20 V/µs; gate open circuit; snubberless condition | 12   | -    | -   | A/ms |
|                                |                                       | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; I <sub>T(RMS)</sub> = 16 A; dV <sub>com</sub> /dt = 10 V/µs; gate open circuit                        | 15   | -    | -   | A/ms |
|                                |                                       | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; I <sub>T(RMS)</sub> = 16 A; dV <sub>com</sub> /dt = 1 V/µs; gate open circuit                         | 20   | -    | -   | A/ms |





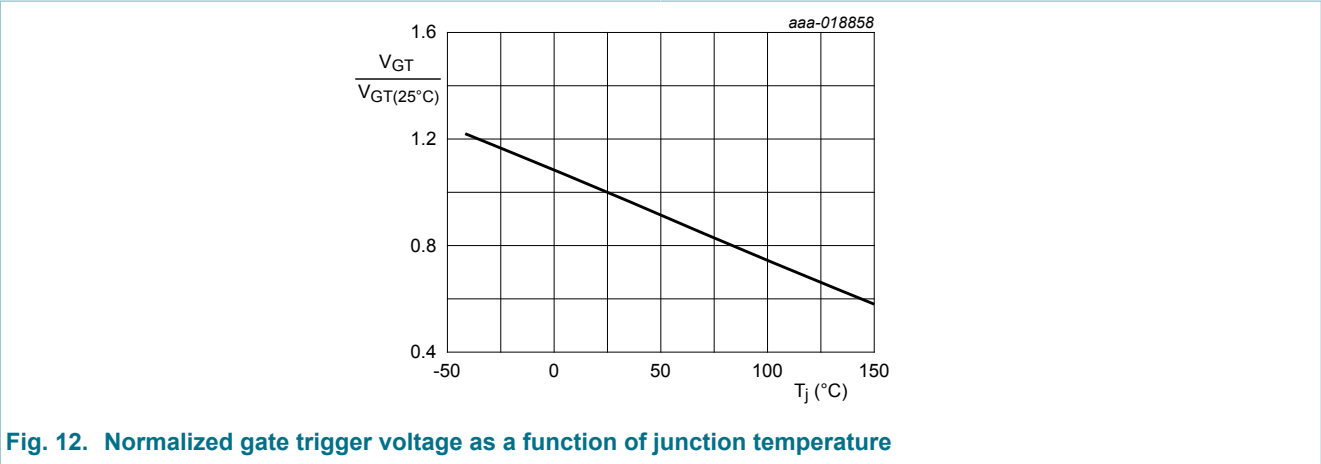


Fig. 12. Normalized gate trigger voltage as a function of junction temperature

## 12. Package outline



Fig. 13. Package outline TO-220F (SOT186A)

## 13. Legal information

### 13.1 Data sheet status

| Document status [1][2]         | Product status [3] | Definition  |
|--------------------------------|--------------------|---|
| Objective [short] data sheet   | Development        | This document contains data from the objective specification for product development. |
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 Date of release: 30 July 2015

## Данный компонент на территории Российской Федерации

### Вы можете приобрести в компании MosChip.

Для оперативного оформления запроса Вам необходимо перейти по данной ссылке:

<http://moschip.ru/get-element>

Вы можете разместить у нас заказ для любого Вашего проекта, будь то серийное производство или разработка единичного прибора.

В нашем ассортименте представлены ведущие мировые производители активных и пассивных электронных компонентов.

Нашей специализацией является поставка электронной компонентной базы двойного назначения, продукции таких производителей как XILINX, Intel (ex.ALTERA), Vicor, Microchip, Texas Instruments, Analog Devices, Mini-Circuits, Amphenol, Glenair.

Сотрудничество с глобальными дистрибьюторами электронных компонентов, предоставляет возможность заказывать и получать с международных складов практически любой перечень компонентов в оптимальные для Вас сроки.

На всех этапах разработки и производства наши партнеры могут получить квалифицированную поддержку опытных инженеров.

Система менеджмента качества компании отвечает требованиям в соответствии с ГОСТ Р ИСО 9001, ГОСТ РВ 0015-002 и ЭС РД 009

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